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[1. DMEA132-001: Miniaturized RF over Fiber](#)

Release Date: 04-24-2013 Open Date: 05-24-2013 Due Date: 06-26-2013 Close Date: 06-26-2013

OBJECTIVE: Design and prototype a capability to use fiber optic cable to simultaneously distribute power (i.e power over fiber) while providing full duplex information flow. The capability will allow miniature microwave system components to be distributed over a relatively long distance (i.e. 30 meters or more) via fiber optics. For example, a processing node (within a microwave system) provid ...

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[2. DMEA132-002: High Resolution Three-Dimensional Digital Reconstruction of Integrated Circuits](#)

Release Date: 04-24-2013 Open Date: 05-24-2013 Due Date: 06-26-2013 Close Date: 06-26-2013

OBJECTIVE: Develop a system for the accurate identification and analysis of semiconductor materials with integrated, high-resolution imaging capability for the three-dimensional digital reconstruction of integrated circuits (ICs). DESCRIPTION: As semiconductor geometries continue to diminish, so too does the applicability of traditional sample preparation tools. As the thickness of metal l ...

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[3. DMEA122-001: High Speed, High Resolution X-ray System for Inspecting Integrated Circuits](#)

Release Date: 04-24-2012 Open Date: 05-24-2012 Due Date: 06-27-2012 Close Date: 06-27-2012

OBJECTIVE: Develop an affordable x-ray microscope system for use in performing integrated circuit (IC) reverse engineering. DESCRIPTION: X-ray microscopy using a synchrotron as the x-ray source has been demonstrated to be an extremely valuable tool in the performance of high throughput integrated circuit evaluation and reverse engineering efforts. However, synchrotron x-ray sources are prohi ...

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